Application/Control No. Applicant(s)/Patent Under Reexamination 10/788,542 SCHEER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Vivian Chen 1773 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2007/0203283 08-2007 Scheer, Frederic Α 524/442 В US-2004/0143072 07-2004 Lewis et al. 525/417 US-C US-D US-Е US-F US-G US-Н US-US-J US-K US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 2001-026658 01-2001 JP Ν Yoshida et al JP 2003-171544 06-2003 JP 0 Takagi et al Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

W

Х